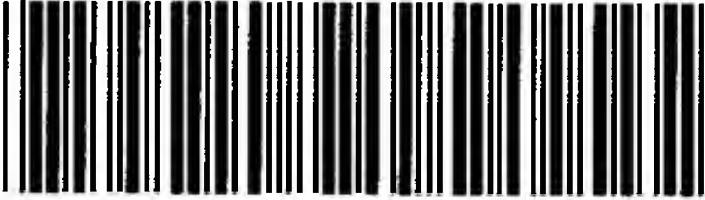


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/579,024	JIN ET AL.	
	Examiner	Art Unit	
	TAN TRINH	2618	

SEARCHED			
Class	Subclass	Date	Examiner
455	511	2/6/2008	TT
	108		
	403		
	422		
370	342		
	493		
	435		
	349		
	433		
	528		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	2/6/2008	TT